


<b>Search Notes</b>  	<b>Application/Control No.</b>  10787152	<b>Applicant(s)/Patent Under Reexamination</b>  SAKAI ET AL.
	<b>Examiner</b>  Yeh, Eueng-nan	<b>Art Unit</b>  2624

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
(382/243) text search - see search printouts	2007/07/05	ey
(382/239) text search - see search printouts	2007/07/05	ey
(358/426.12) text search - see search printouts	2007/07/05	ey
EAST text serach - see search printout	2007/06/26	ey
PALM inventor search	2007/06/26	ey
IEEE Xplore text search - see search printout	2007/07/19	ey
SPIE test search - see search printout	2007/07/19	ey
CiteSeer text search - see search printout	2007/07/19	ey
EAST text search (consulted W.B. Chen AU 2624)	2007/07/18	ey

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>